Search Notes

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OYAKE ET AL.

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Art Unit

Applicant(s)/Patent under Reexamination

Anthony H. Nguyen

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Class	Subclass	Date	Examiner
101	483,487	1/26/2006	HAI
430	322-325	1/26/2006	HAI
425	403	1/26/2006	HAI
369	273	1/26/2006	HAI
Above	See S.N.	1/26/2006	HAI
Above	updated	8/11/2006	HAI

INT	INTERFERENCE SEARCHED				
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